

FDC2612

200V N-Channel PowerTrench® MOSFET

General Description

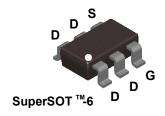
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $R_{\text{DS}(\text{ON})}$ and fast switching speed.

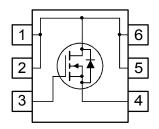
Applications

• DC/DC converter

Features

- 1.1 A, 200 V. $R_{DS(ON)} = 725 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$
- High performance trench technology for extremely low $R_{\text{DS(ON)}}$
- High power and current handling capability
- · Fast switching speed
- Low gate charge (8nC typical)





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	
V _{DSS}	Drain-Source Voltage		200	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1a)	1.1	Α
	- Pulsed		4	
P _D	Maximum Power Dissipation	(Note 1a)	1.6	W
		(Note 1b)	0.8	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R _{θJC}	Thermal Resistance, Junction-to-Case	(Note 1)	30	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity	
.262	FDC2612	7"	8mm	3000 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		ı	1		ı
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	200			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		246		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 160 V, V _{GS} = 0 V			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2	4	4.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-8.7		mV/°C
R _{DS(on)}	Static Drain–Source On Resistance	V_{GS} = 10 V, I_{D} = 1.1 A V_{GS} = 10 V, I_{D} = 1.1 A, T_{J} = 125°C		605 1133	725 1430	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	4			Α
g FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 1.1 \text{ A}$		4.4		S
Dynami	c Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 100 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		234		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		18		pF
C _{rss}	Reverse Transfer Capacitance			8		pF
Switchir	ng Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 100 \text{ V}, \qquad I_{D} = 1 \text{ A},$		6	12	ns
t _r	Turn-On Rise Time	V_{GS} = 10 V, R_{GEN} = 6 Ω		6	12	ns
$t_{d(off)}$	Turn-Off Delay Time			17	30	ns
t _f	Turn-Off Fall Time			8	16	ns
Qg	Total Gate Charge	V _{DS} = 100 V, I _D = 1.1 A,		8	11	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		1.6		nC
Q _{gd}	Gate-Drain Charge			2.2		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	9			1.3	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{S} = 1.3 \text{ A}(\text{Note 2})$		0.8	1.2	V
rr	Diode Reverse Recovery Time	I _F = 1.1A,		74.5		nS
Q_{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (Note 2)		194		nC

Notes:

1.R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 78°C/W when mounted on a 1in² pad of 2 oz copper

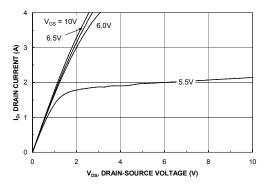


156°C/W when mounted on a minimum pad of 2 oz b) copper

Scale 1: 1 on letter size paper

2. Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%

Typical Characteristics



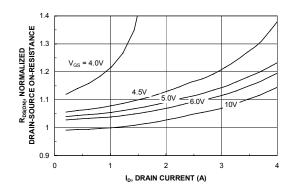
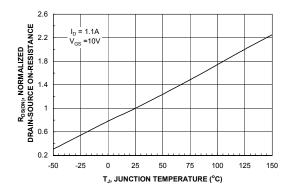


Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



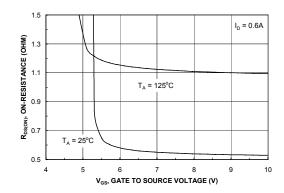
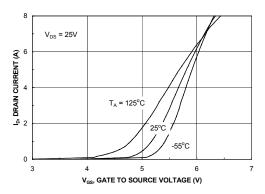


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



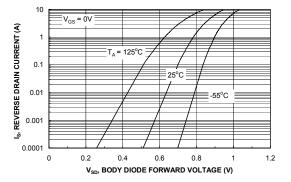
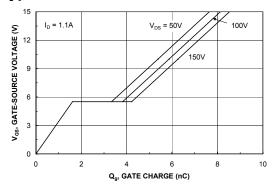


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



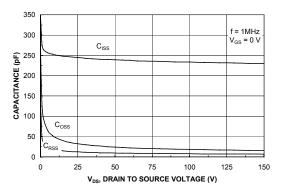
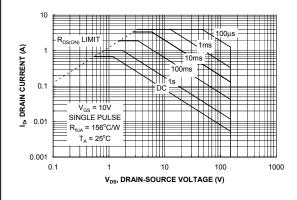


Figure 7. Gate Charge Characteristics.





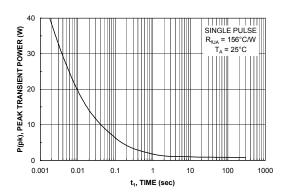


Figure 9. Maximum Safe Operating Area.



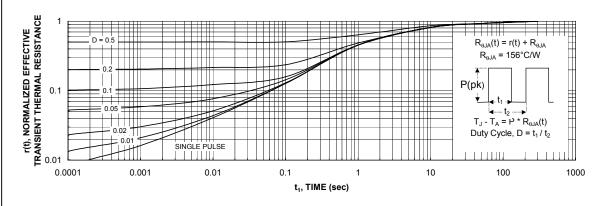


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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